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[Understanding Embedded - FPGAs \(Field Programmable Gate Array\)](#)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications,

Details

Product Status	Active
Number of LABs/CLBs	2880
Number of Logic Elements/Cells	-
Total RAM Bits	-
Number of I/O	203
Number of Gates	48000
Voltage - Supply	2.25V ~ 5.25V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 70°C (TA)
Package / Case	256-BGA
Supplier Device Package	256-FPBGA (17x17)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/a54sx32a-fg256

Routing Resources

The routing and interconnect resources of SX-A devices are in the top two metal layers above the logic modules (Figure 1-1 on page 1-1), providing optimal use of silicon, thus enabling the entire floor of the device to be spanned with an uninterrupted grid of logic modules. Interconnection between these logic modules is achieved using the Actel patented metal-to-metal programmable antifuse interconnect elements. The antifuses are normally open circuits and, when programmed, form a permanent low-impedance connection.

Clusters and SuperClusters can be connected through the use of two innovative local routing resources called FastConnect and DirectConnect, which enable extremely fast and predictable interconnection of modules within Clusters and SuperClusters (Figure 1-5 on page 1-4 and Figure 1-6 on page 1-4). This routing architecture also dramatically reduces the number of antifuses required to complete a circuit, ensuring the highest possible performance, which is often required in applications such as fast counters, state machines, and data path logic. The interconnect elements (i.e., the antifuses and metal tracks) have lower capacitance and lower resistance than any other device of similar capacity, leading to the fastest signal propagation in the industry.

DirectConnect is a horizontal routing resource that provides connections from a C-cell to its neighboring R-Cell in a given SuperCluster. DirectConnect uses a hardwired signal path requiring no programmable

interconnection to achieve its fast signal propagation time of less than 0.1 ns.

FastConnect enables horizontal routing between any two logic modules within a given SuperCluster, and vertical routing with the SuperCluster immediately below it. Only one programmable connection is used in a FastConnect path, delivering a maximum pin-to-pin propagation time of 0.3 ns.

In addition to DirectConnect and FastConnect, the architecture makes use of two globally oriented routing resources known as segmented routing and high-drive routing. The Actel segmented routing structure provides a variety of track lengths for extremely fast routing between SuperClusters. The exact combination of track lengths and antifuses within each path is chosen by the 100% automatic place-and-route software to minimize signal propagation delays.

The general system of routing tracks allows any logic module in the array to be connected to any other logic or I/O module. Within this system, most connections typically require three or fewer antifuses, resulting in fast and predictable performance.

The unique local and general routing structure featured in SX-A devices allows 100% pin-locking with full logic utilization, enables concurrent printed circuit board (PCB) development, reduces design time, and allows designers to achieve performance goals with minimum effort.

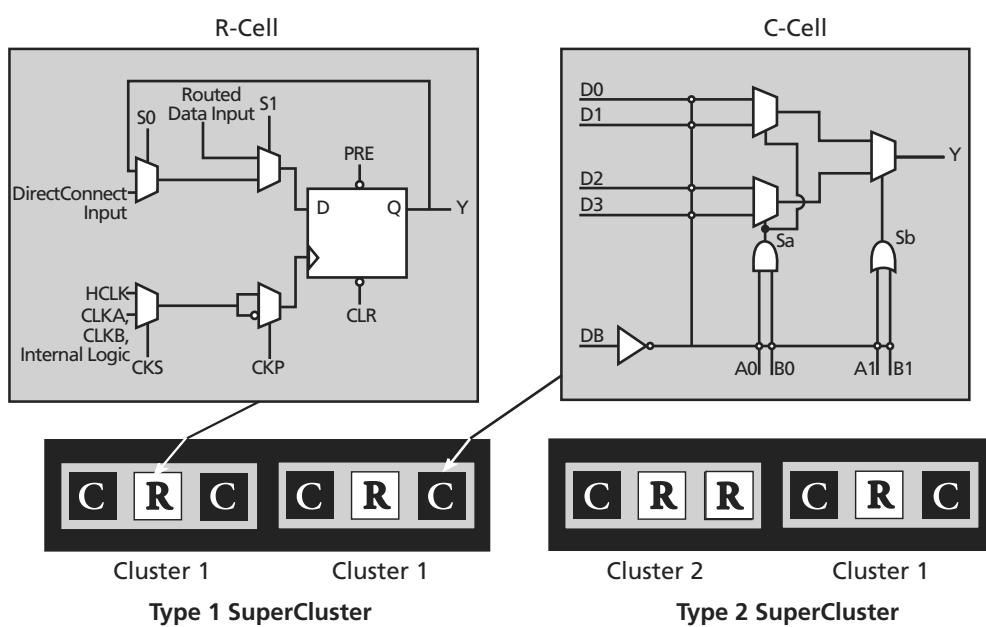


Figure 1-4 • Cluster Organization

Boundary-Scan Testing (BST)

All SX-A devices are IEEE 1149.1 compliant and offer superior diagnostic and testing capabilities by providing Boundary Scan Testing (BST) and probing capabilities. The BST function is controlled through the special JTAG pins (TMS, TDI, TCK, TDO, and TRST). The functionality of the JTAG pins is defined by two available modes: Dedicated and Flexible. TMS cannot be employed as a user I/O in either mode.

Dedicated Mode

In Dedicated mode, all JTAG pins are reserved for BST; designers cannot use them as regular I/Os. An internal pull-up resistor is automatically enabled on both TMS and TDI pins, and the TMS pin will function as defined in the IEEE 1149.1 (JTAG) specification.

To select Dedicated mode, the user must reserve the JTAG pins in Actel's Designer software. Reserve the JTAG pins by checking the **Reserve JTAG** box in the Device Selection Wizard (Figure 1-12).

The default for the software is Flexible mode; all boxes are unchecked. Table 1-5 lists the definitions of the options in the Device Selection Wizard.

Flexible Mode

In Flexible mode, TDI, TCK, and TDO may be employed as either user I/Os or as JTAG input pins. The internal resistors on the TMS and TDI pins are not present in flexible JTAG mode.

To select the Flexible mode, uncheck the **Reserve JTAG** box in the Device Selection Wizard dialog in the Actel Designer software. In Flexible mode, TDI, TCK, and TDO pins may function as user I/Os or BST pins. The functionality is controlled by the BST Test Access Port (TAP) controller. The TAP controller receives two control inputs, TMS and TCK. Upon power-up, the TAP controller enters the Test-Logic-Reset state. In this state, TDI, TCK, and TDO function as user I/Os. The TDI, TCK, and TDO are transformed from user I/Os into BST pins when a rising edge on TCK is detected while TMS is at logic low. To return to Test-Logic Reset state, TMS must be high for at least five TCK cycles. **An external 10 k pull-up resistor to V_{CC} should be placed on the TMS pin to pull it High by default.**

Table 1-6 describes the different configuration requirements of BST pins and their functionality in different modes.

Table 1-6 • Boundary-Scan Pin Configurations and Functions

Mode	Designer "Reserve JTAG" Selection	TAP Controller State
Dedicated (JTAG)	Checked	Any
Flexible (User I/O)	Unchecked	Test-Logic-Reset
Flexible (JTAG)	Unchecked	Any EXCEPT Test-Logic-Reset

Figure 1-12 • Device Selection Wizard

Table 1-5 • Reserve Pin Definitions

Pin	Function
Reserve JTAG	Keeps pins from being used and changes the behavior of JTAG pins (no pull-up on TMS)
Reserve JTAG Test Reset	Regular I/O or JTAG reset with an internal pull-up
Reserve Probe	Keeps pins from being used or regular I/O

TRST Pin

The TRST pin functions as a dedicated Boundary-Scan Reset pin when the **Reserve JTAG Test Reset** option is selected as shown in Figure 1-12. An internal pull-up resistor is permanently enabled on the TRST pin in this mode. Actel recommends connecting this pin to ground in normal operation to keep the JTAG state controller in the Test-Logic-Reset state. When JTAG is being used, it can be left floating or can be driven high.

When the **Reserve JTAG Test Reset** option is not selected, this pin will function as a regular I/O. If unused as an I/O in the design, it will be configured as a tristated output.

JTAG Instructions

Table 1-7 lists the supported instructions with the corresponding IR codes for SX-A devices.

Table 1-8 lists the codes returned after executing the IDCODE instruction for SX-A devices. Note that bit 0 is always '1'. Bits 11-1 are always '02F', which is the Actel manufacturer code.

Table 1-7 • JTAG Instruction Code

Instructions (IR4:IR0)	Binary Code
EXTEST	00000
SAMPLE/PRELOAD	00001
INTEST	00010
USERCODE	00011
IDCODE	00100
HighZ	01110
CLAMP	01111
Diagnostic	10000
BYPASS	11111
Reserved	All others

Table 1-8 • JTAG Instruction Code

Device	Process	Revision	Bits 31-28	Bits 27-12
A54SX08A	0.22 μ	0	8, 9	40B4, 42B4
		1	A, B	40B4, 42B4
A54SX16A	0.22 μ	0	9	40B8, 42B8
		1	B	40B8, 42B8
	0.25 μ	1	B	22B8
A54SX32A	0.2 2 μ	0	9	40BD, 42BD
		1	B	40BD, 42BD
	0.25 μ	1	B	22BD
A54SX72A	0.22 μ	0	9	40B2, 42B2
		1	B	40B2, 42B2
	0.25 μ	1	B	22B2

Related Documents

Application Notes

Global Clock Networks in Actel's Antifuse Devices

http://www.actel.com/documents/GlobalClk_AN.pdf

Using A54SX72A and RT54SX72S Quadrant Clocks

http://www.actel.com/documents/QCLK_AN.pdf

Implementation of Security in Actel Antifuse FPGAs

http://www.actel.com/documents/Antifuse_Security_AN.pdf

Actel eX, SX-A, and RTSX-S I/Os

http://www.actel.com/documents/AntifuseIO_AN.pdf

Actel SX-A and RT54SX-S Devices in Hot-Swap and Cold-Sparing Applications

http://www.actel.com/documents/HotSwapColdSparing_AN.pdf

Programming Antifuse Devices

http://www.actel.com/documents/AntifuseProgram_AN.pdf

Datasheets

HiRel SX-A Family FPGAs

http://www.actel.com/documents/HRSXA_DS.pdf

SX-A Automotive Family FPGAs

http://www.actel.com/documents/SXA_Auto_DS.pdf

User's Guides

Silicon Sculptor User's Guide

http://www.actel.com/documents/SiliSculptII_Sculpt3_ug.pdf

Figure 2-2 shows the 3.3 V PCI V/I curve and the minimum and maximum PCI drive characteristics of the SX-A family.

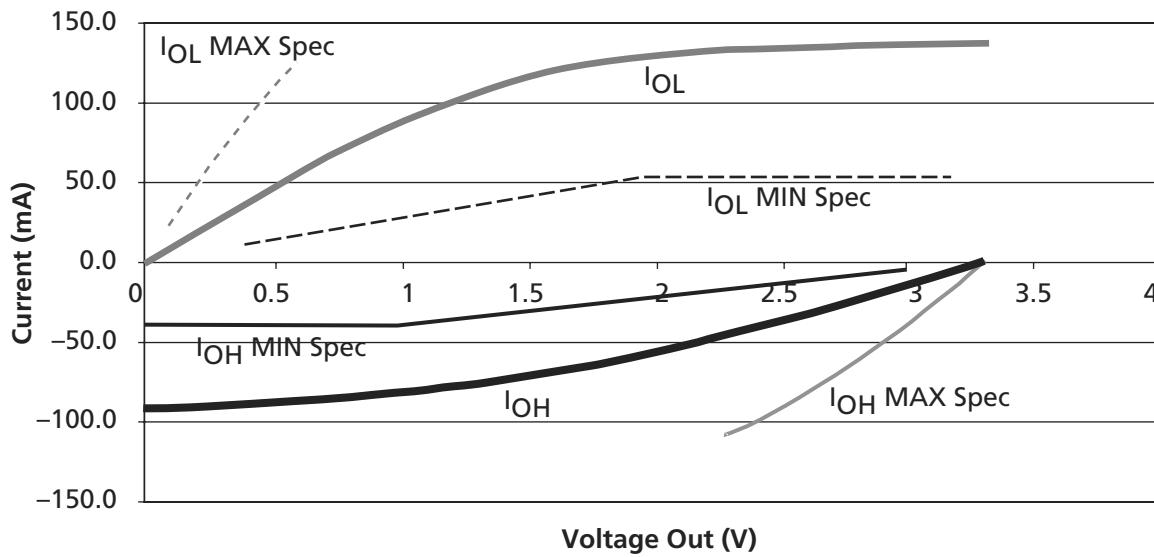


Figure 2-2 • 3.3 V PCI V/I Curve for SX-A Family

$$I_{OH} = (98.0V_{CCI}) * (V_{OUT} - V_{CCI}) * (V_{OUT} + 0.4V_{CCI})$$

for $0.7V_{CCI} < V_{OUT} < V_{CCI}$

EQ 2-3

$$I_{OL} = (256V_{CCI}) * V_{OUT} * (V_{CCI} - V_{OUT})$$

for $0V < V_{OUT} < 0.18V_{CCI}$

EQ 2-4

To determine the heat sink's thermal performance, use the following equation:

$$\theta_{JA(TOTAL)} = \theta_{JC} + \theta_{CS} + \theta_{SA}$$

EQ 2-14

where:

$$\theta_{CS} = 0.37^{\circ}\text{C}/\text{W}$$

= thermal resistance of the interface material between the case and the heat sink, usually provided by the thermal interface manufacturer

$$\theta_{SA} = \text{thermal resistance of the heat sink in } ^{\circ}\text{C}/\text{W}$$

$$\theta_{SA} = \theta_{JA(TOTAL)} - \theta_{JC} - \theta_{CS}$$

EQ 2-15

$$\theta_{SA} = 13.33^{\circ}\text{C}/\text{W} - 3.20^{\circ}\text{C}/\text{W} - 0.37^{\circ}\text{C}/\text{W}$$

$$\theta_{SA} = 9.76^{\circ}\text{C}/\text{W}$$

A heat sink with a thermal resistance of $9.76^{\circ}\text{C}/\text{W}$ or better should be used. Thermal resistance of heat sinks is a function of airflow. The heat sink performance can be significantly improved with the presence of airflow.

Carefully estimating thermal resistance is important in the long-term reliability of an Actel FPGA. Design engineers should always correlate the power consumption of the device with the maximum allowable power dissipation of the package selected for that device, using the provided thermal resistance data.

Note: The values may vary depending on the application.

Output Buffer Delays

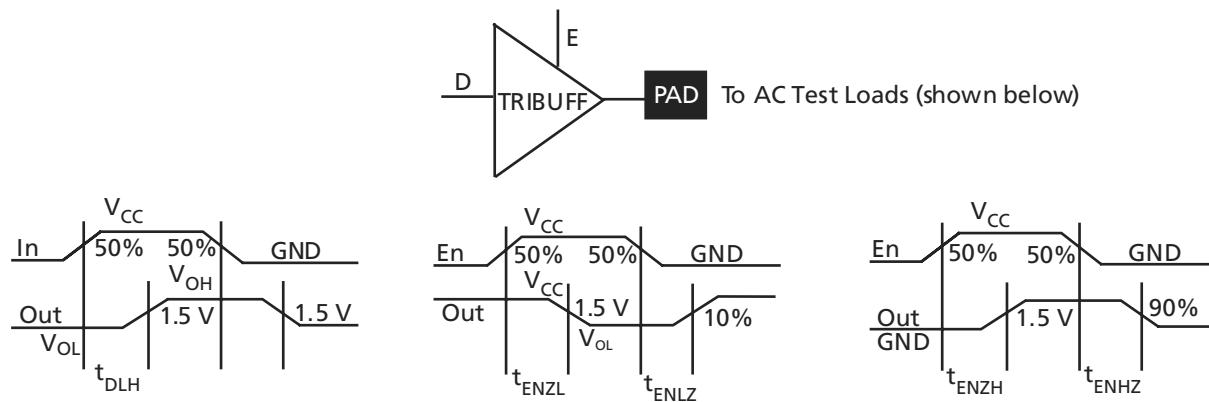


Figure 2-4 • Output Buffer Delays

AC Test Loads

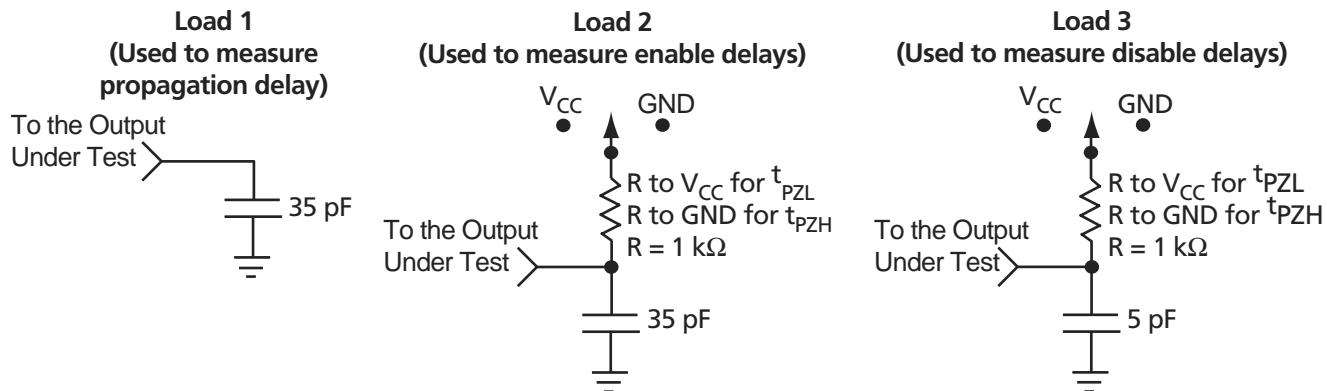


Figure 2-5 • AC Test Loads

Table 2-14 • A54SX08A Timing Characteristics (Continued)
 (Worst-Case Commercial Conditions, $V_{CCA} = 2.25\text{ V}$, $V_{CCI} = 3.0\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	-2 Speed	-1 Speed	Std. Speed	-F Speed	Units
		Min.	Max.	Min.	Max.	
t_{INYH}	Input Data Pad to Y High 5 V PCI	0.5	0.6	0.7	0.9	ns
t_{INYL}	Input Data Pad to Y Low 5 V PCI	0.8	0.9	1.1	1.5	ns
t_{INYH}	Input Data Pad to Y High 5 V TTL	0.5	0.6	0.7	0.9	ns
t_{INYL}	Input Data Pad to Y Low 5 V TTL	0.8	0.9	1.1	1.5	ns
Input Module Predicted Routing Delays²						
t_{IRD1}	FO = 1 Routing Delay	0.3	0.3	0.4	0.6	ns
t_{IRD2}	FO = 2 Routing Delay	0.5	0.5	0.6	0.8	ns
t_{IRD3}	FO = 3 Routing Delay	0.6	0.7	0.8	1.1	ns
t_{IRD4}	FO = 4 Routing Delay	0.8	0.9	1	1.4	ns
t_{IRD8}	FO = 8 Routing Delay	1.4	1.5	1.8	2.5	ns
t_{IRD12}	FO = 12 Routing Delay	2	2.2	2.6	3.6	ns

Notes:

1. For dual-module macros, use $t_{PD} + t_{RD1} + t_{PDn}$, $t_{RCO} + t_{RD1} + t_{PDn}$, or $t_{PD1} + t_{RD1} + t_{SUD}$, whichever is appropriate.
2. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.

Table 2-22 • A54SX16A Timing Characteristics
 (Worst-Case Commercial Conditions $V_{CCA} = 2.25\text{ V}$, $V_{CCI} = 2.25\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	-3 Speed*	-2 Speed	-1 Speed	Std. Speed	-F Speed	Units
		Min.	Max.	Min.	Max.	Min.	
Dedicated (Hardwired) Array Clock Networks							
t_{HCKH}	Input Low to High (Pad to R-cell Input)	1.2	1.4	1.6	1.8	2.8	ns
t_{HCKL}	Input High to Low (Pad to R-cell Input)	1.0	1.1	1.2	1.5	2.2	ns
t_{HPWH}	Minimum Pulse Width High	1.4	1.7	1.9	2.2	3.0	ns
t_{HPWL}	Minimum Pulse Width Low	1.4	1.7	1.9	2.2	3.0	ns
t_{HCKSW}	Maximum Skew	0.3	0.3	0.4	0.4	0.7	ns
t_{HP}	Minimum Period	2.8	3.4	3.8	4.4	6.0	ns
f_{HMAX}	Maximum Frequency	357	294	263	227	167	MHz
Routed Array Clock Networks							
t_{RCKH}	Input Low to High (Light Load) (Pad to R-cell Input)	1.0	1.2	1.3	1.6	2.2	ns
t_{RCKL}	Input High to Low (Light Load) (Pad to R-cell Input)	1.1	1.3	1.5	1.7	2.4	ns
t_{RCKH}	Input Low to High (50% Load) (Pad to R-cell Input)	1.1	1.3	1.5	1.7	2.4	ns
t_{RCKL}	Input High to Low (50% Load) (Pad to R-cell Input)	1.1	1.3	1.5	1.7	2.4	ns
t_{RCKH}	Input Low to High (100% Load) (Pad to R-cell Input)	1.3	1.5	1.7	2.0	2.8	ns
t_{RCKL}	Input High to Low (100% Load) (Pad to R-cell Input)	1.3	1.5	1.7	2.0	2.8	ns
t_{RPWH}	Minimum Pulse Width High	1.4	1.7	1.9	2.2	3.0	ns
t_{RPWL}	Minimum Pulse Width Low	1.4	1.7	1.9	2.2	3.0	ns
t_{RCKSW}	Maximum Skew (Light Load)	0.8	0.9	1.0	1.2	1.7	ns
t_{RCKSW}	Maximum Skew (50% Load)	0.8	0.9	1.0	1.2	1.7	ns
t_{RCKSW}	Maximum Skew (100% Load)	1.0	1.1	1.3	1.5	2.1	ns

Note: *All -3 speed grades have been discontinued.

Table 2-26 • A54SX16A Timing Characteristics
 (Worst-Case Commercial Conditions $V_{CCA} = 2.25\text{ V}$, $V_{CCI} = 3.0\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	-3 Speed¹	-2 Speed	-1 Speed	Std. Speed	-F Speed	Units
		Min.	Max.	Min.	Max.	Min.	
3.3 V PCI Output Module Timing²							
t_{DLH}	Data-to-Pad Low to High	2.0	2.3	2.6	3.1	4.3	ns
t_{DHL}	Data-to-Pad High to Low	2.2	2.5	2.8	3.3	4.6	ns
t_{ENZL}	Enable-to-Pad, Z to L	1.4	1.7	1.9	2.2	3.1	ns
t_{ENZH}	Enable-to-Pad, Z to H	2.0	2.3	2.6	3.1	4.3	ns
t_{ENLZ}	Enable-to-Pad, L to Z	2.5	2.8	3.2	3.8	5.3	ns
t_{ENHZ}	Enable-to-Pad, H to Z	2.2	2.5	2.8	3.3	4.6	ns
d_{TLH}^3	Delta Low to High	0.025	0.03	0.03	0.04	0.045	ns/pF
d_{THL}^3	Delta High to Low	0.015	0.015	0.015	0.015	0.025	ns/pF
3.3 V LVTTL Output Module Timing⁴							
t_{DLH}	Data-to-Pad Low to High	2.8	3.2	3.6	4.3	6.0	ns
t_{DHL}	Data-to-Pad High to Low	2.7	3.1	3.5	4.1	5.7	ns
t_{DHLS}	Data-to-Pad High to Low—low slew	9.5	10.9	12.4	14.6	20.4	ns
t_{ENZL}	Enable-to-Pad, Z to L	2.2	2.6	2.9	3.4	4.8	ns
t_{ENZLS}	Enable-to-Pad, Z to L—low slew	15.8	18.9	21.3	25.4	34.9	ns
t_{ENZH}	Enable-to-Pad, Z to H	2.8	3.2	3.6	4.3	6.0	ns
t_{ENLZ}	Enable-to-Pad, L to Z	2.9	3.3	3.7	4.4	6.2	ns
t_{ENHZ}	Enable-to-Pad, H to Z	2.7	3.1	3.5	4.1	5.7	ns
d_{TLH}^3	Delta Low to High	0.025	0.03	0.03	0.04	0.045	ns/pF
d_{THL}^3	Delta High to Low	0.015	0.015	0.015	0.015	0.025	ns/pF
d_{THLS}^3	Delta High to Low—low slew	0.053	0.053	0.067	0.073	0.107	ns/pF

Notes:

1. All -3 speed grades have been discontinued.
2. Delays based on 10 pF loading and 25 Ω resistance.
3. To obtain the slew rate, substitute the appropriate Delta value, load capacitance, and the V_{CCI} value into the following equation:

$$\text{Slew Rate [V/ns]} = (0.1 * V_{CCI} - 0.9 * V_{CCI}) / (C_{load} * d_{T[LH|HL|HLS]})$$

where C_{load} is the load capacitance driven by the I/O in pF.
 $d_{T[LH|HL|HLS]}$ is the worst case delta value from the datasheet in ns/pF.
4. Delays based on 35 pF loading.

Table 2-28 • A54SX32A Timing Characteristics
 (Worst-Case Commercial Conditions, $V_{CCA} = 2.25\text{ V}$, $V_{CCI} = 3.0\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	-3 Speed¹		-2 Speed		-1 Speed		Std. Speed	-F Speed	Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
C-Cell Propagation Delays²										
t_{PD}	Internal Array Module	0.8	0.9	1.1	1.2	1.7	ns			
Predicted Routing Delays³										
t_{DC}	FO = 1 Routing Delay, Direct Connect	0.1	0.1	0.1	0.1	0.1	0.1	ns		
t_{FC}	FO = 1 Routing Delay, Fast Connect	0.3	0.3	0.3	0.4	0.4	0.6	ns		
t_{RD1}	FO = 1 Routing Delay	0.3	0.3	0.4	0.5	0.5	0.6	ns		
t_{RD2}	FO = 2 Routing Delay	0.4	0.5	0.5	0.6	0.6	0.8	ns		
t_{RD3}	FO = 3 Routing Delay	0.5	0.6	0.7	0.8	0.8	1.1	ns		
t_{RD4}	FO = 4 Routing Delay	0.7	0.8	0.9	1.0	1.0	1.4	ns		
t_{RD8}	FO = 8 Routing Delay	1.2	1.4	1.5	1.8	1.8	2.5	ns		
t_{RD12}	FO = 12 Routing Delay	1.7	2.0	2.2	2.6	2.6	3.6	ns		
R-Cell Timing										
t_{RCO}	Sequential Clock-to-Q	0.6	0.7	0.8	0.9	1.3	ns			
t_{CLR}	Asynchronous Clear-to-Q	0.5	0.6	0.6	0.8	1.0	ns			
t_{PRESET}	Asynchronous Preset-to-Q	0.6	0.7	0.7	0.9	1.2	ns			
t_{SUD}	Flip-Flop Data Input Set-Up	0.6	0.7	0.8	0.9	1.2	ns			
t_{HD}	Flip-Flop Data Input Hold	0.0	0.0	0.0	0.0	0.0	ns			
t_{WASYN}	Asynchronous Pulse Width	1.2	1.4	1.5	1.8	2.5	ns			
$t_{RECASYN}$	Asynchronous Recovery Time	0.3	0.4	0.4	0.5	0.7	ns			
t_{HASYN}	Asynchronous Removal Time	0.3	0.3	0.3	0.4	0.6	ns			
t_{MPW}	Clock Pulse Width	1.4	1.6	1.8	2.1	2.9	ns			
Input Module Propagation Delays										
t_{INYH}	Input Data Pad to Y High 2.5 V LVC MOS	0.6	0.7	0.8	0.9	1.2	ns			
t_{INYL}	Input Data Pad to Y Low 2.5 V LVC MOS	1.2	1.3	1.5	1.8	2.5	ns			
t_{INYH}	Input Data Pad to Y High 3.3 V PCI	0.5	0.6	0.6	0.7	1.0	ns			
t_{INYL}	Input Data Pad to Y Low 3.3 V PCI	0.6	0.7	0.8	0.9	1.3	ns			
t_{INYH}	Input Data Pad to Y High 3.3 V LV TTL	0.8	0.9	1.0	1.2	1.6	ns			
t_{INYL}	Input Data Pad to Y Low 3.3 V LV TTL	1.4	1.6	1.8	2.2	3.0	ns			

Notes:

1. All -3 speed grades have been discontinued.
2. For dual-module macros, use $t_{PD} + t_{RD1} + t_{PDn}$, $t_{RCO} + t_{RD1} + t_{PDn}$, or $t_{PD1} + t_{RD1} + t_{SUD}$, whichever is appropriate.
3. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.

Table 2-33 • A54SX32A Timing Characteristics
 (Worst-Case Commercial Conditions $V_{CCA} = 2.25\text{ V}$, $V_{CCI} = 3.0\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	-3 Speed¹	-2 Speed	-1 Speed	Std. Speed	-F Speed	Units
		Min.	Max.	Min.	Max.	Min.	
3.3 V PCI Output Module Timing²							
t_{DLH}	Data-to-Pad Low to High	1.9	2.2	2.4	2.9	4.0	ns
t_{DHL}	Data-to-Pad High to Low	2.0	2.3	2.6	3.1	4.3	ns
t_{ENZL}	Enable-to-Pad, Z to L	1.4	1.7	1.9	2.2	3.1	ns
t_{ENZH}	Enable-to-Pad, Z to H	1.9	2.2	2.4	2.9	4.0	ns
t_{ENLZ}	Enable-to-Pad, L to Z	2.5	2.8	3.2	3.8	5.3	ns
t_{ENHZ}	Enable-to-Pad, H to Z	2.0	2.3	2.6	3.1	4.3	ns
d_{TLH}^3	Delta Low to High	0.025	0.03	0.03	0.04	0.045	ns/pF
d_{THL}^3	Delta High to Low	0.015	0.015	0.015	0.015	0.025	ns/pF
3.3 V LVTTL Output Module Timing⁴							
t_{DLH}	Data-to-Pad Low to High	2.6	3.0	3.4	4.0	5.6	ns
t_{DHL}	Data-to-Pad High to Low	2.6	3.0	3.3	3.9	5.5	ns
t_{DHLS}	Data-to-Pad High to Low—low slew	9.0	10.4	11.8	13.8	19.3	ns
t_{ENZL}	Enable-to-Pad, Z to L	2.2	2.6	2.9	3.4	4.8	ns
t_{ENZLS}	Enable-to-Pad, Z to L—low slew	15.8	18.9	21.3	25.4	34.9	ns
t_{ENZH}	Enable-to-Pad, Z to H	2.6	3.0	3.4	4.0	5.6	ns
t_{ENLZ}	Enable-to-Pad, L to Z	2.9	3.3	3.7	4.4	6.2	ns
t_{ENHZ}	Enable-to-Pad, H to Z	2.6	3.0	3.3	3.9	5.5	ns
d_{TLH}^3	Delta Low to High	0.025	0.03	0.03	0.04	0.045	ns/pF
d_{THL}^3	Delta High to Low	0.015	0.015	0.015	0.015	0.025	ns/pF
d_{THLS}^3	Delta High to Low—low slew	0.053	0.053	0.067	0.073	0.107	ns/pF

Notes:

1. All -3 speed grades have been discontinued.
2. Delays based on 10 pF loading and 25 Ω resistance.
3. To obtain the slew rate, substitute the appropriate Delta value, load capacitance, and the V_{CCI} value into the following equation:

$$\text{Slew Rate [V/ns]} = (0.1 * V_{CCI} - 0.9 * V_{CCI}) / (C_{load} * d_{T[LH|HL|HLS]})$$

where C_{load} is the load capacitance driven by the I/O in pF

$d_{T[LH|HL|HLS]}$ is the worst case delta value from the datasheet in ns/pF.
4. Delays based on 35 pF loading.

Table 2-35 • A54SX72A Timing Characteristics (Continued)
 (Worst-Case Commercial Conditions, $V_{CCA} = 2.25\text{ V}$, $V_{CCI} = 3.0\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	-3 Speed¹	-2 Speed	-1 Speed	Std. Speed	-F Speed	Units
		Min.	Max.	Min.	Max.	Min.	
t_{INYH}	Input Data Pad to Y High 5 V PCI	0.5	0.6	0.7	0.8	1.1	ns
t_{INYL}	Input Data Pad to Y Low 5 V PCI	0.8	0.9	1.0	1.2	1.6	ns
t_{INYH}	Input Data Pad to Y High 5 V TTL	0.7	0.8	0.9	1.0	1.4	ns
t_{INYL}	Input Data Pad to Y Low 5 V TTL	0.9	1.1	1.2	1.4	1.9	ns
Input Module Predicted Routing Delays³							
t_{IRD1}	FO = 1 Routing Delay	0.3	0.3	0.4	0.5	0.7	ns
t_{IRD2}	FO = 2 Routing Delay	0.4	0.5	0.6	0.7	1	ns
t_{IRD3}	FO = 3 Routing Delay	0.5	0.7	0.8	0.9	1.3	ns
t_{IRD4}	FO = 4 Routing Delay	0.7	0.9	1	1.1	1.5	ns
t_{IRD8}	FO = 8 Routing Delay	1.2	1.5	1.7	2.1	2.9	ns
t_{IRD12}	FO = 12 Routing Delay	1.7	2.2	2.5	3	4.2	ns

Notes:

1. All -3 speed grades have been discontinued.
2. For dual-module macros, use $t_{PD} + t_{RD1} + t_{PDn}$, $t_{RCO} + t_{RD1} + t_{PDn}$, or $t_{PD1} + t_{RD1} + t_{SUD}$, whichever is appropriate.
3. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.

Table 2-36 • A54SX72A Timing Characteristics
 (Worst-Case Commercial Conditions $V_{CCA} = 2.25\text{ V}$, $V_{CCI} = 2.25\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	-3 Speed*	-2 Speed	-1 Speed	Std. Speed	-F Speed	Units
		Min.	Max.	Min.	Max.	Min.	
Dedicated (Hardwired) Array Clock Networks							
t_{HCKH}	Input Low to High (Pad to R-cell Input)	1.6	1.9	2.1	2.5	3.8	ns
t_{HCKL}	Input High to Low (Pad to R-cell Input)	1.6	1.9	2.1	2.5	3.8	ns
t_{HPWH}	Minimum Pulse Width High	1.5	1.7	2.0	2.3	3.2	ns
t_{HPWL}	Minimum Pulse Width Low	1.5	1.7	2.0	2.3	3.2	ns
t_{HCKSW}	Maximum Skew	1.4	1.6	1.8	2.1	3.3	ns
t_{HP}	Minimum Period	3.0	3.4	4.0	4.6	6.4	ns
f_{HMAX}	Maximum Frequency	333	294	250	217	156	MHz
Routed Array Clock Networks							
t_{RCKH}	Input Low to High (Light Load) (Pad to R-cell Input)	2.3	2.6	2.9	3.4	4.8	ns
t_{RCKL}	Input High to Low (Light Load) (Pad to R-cell Input)	2.8	3.2	3.7	4.3	6.0	ns
t_{RCKH}	Input Low to High (50% Load) (Pad to R-cell Input)	2.4	2.8	3.2	3.7	5.2	ns
t_{RCKL}	Input High to Low (50% Load) (Pad to R-cell Input)	2.9	3.3	3.8	4.5	6.2	ns
t_{RCKH}	Input Low to High (100% Load) (Pad to R-cell Input)	2.6	3.0	3.4	4.0	5.6	ns
t_{RCKL}	Input High to Low (100% Load) (Pad to R-cell Input)	3.1	3.6	4.0	4.7	6.6	ns
t_{RPWH}	Minimum Pulse Width High	1.5	1.7	2.0	2.3	3.2	ns
t_{RPWL}	Minimum Pulse Width Low	1.5	1.7	2.0	2.3	3.2	ns
t_{RCKSW}	Maximum Skew (Light Load)	1.9	2.2	2.5	3.0	4.1	ns
t_{RCKSW}	Maximum Skew (50% Load)	1.8	2.1	2.4	2.8	3.9	ns
t_{RCKSW}	Maximum Skew (100% Load)	1.8	2.1	2.4	2.8	3.9	ns
Quadrant Array Clock Networks							
t_{QCKH}	Input Low to High (Light Load) (Pad to R-cell Input)	2.6	3.0	3.4	4.0	5.6	ns
t_{QCHKL}	Input High to Low (Light Load) (Pad to R-cell Input)	2.6	3.0	3.3	3.9	5.5	ns
t_{QCKH}	Input Low to High (50% Load) (Pad to R-cell Input)	2.8	3.2	3.6	4.3	6.0	ns
t_{QCHKL}	Input High to Low (50% Load) (Pad to R-cell Input)	2.8	3.2	3.6	4.2	5.9	ns

Note: *All -3 speed grades have been discontinued.

Table 2-41 • A54SX72A Timing Characteristics
 (Worst-Case Commercial Conditions $V_{CCA} = 2.25\text{ V}$, $V_{CCI} = 4.75\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	-3 Speed¹	-2 Speed	-1 Speed	Std. Speed	-F Speed	Units
		Min.	Max.	Min.	Max.	Min.	
5 V PCI Output Module Timing²							
t_{DLH}	Data-to-Pad Low to High	2.7	3.1	3.5	4.1	5.7	ns
t_{DHL}	Data-to-Pad High to Low	3.4	3.9	4.4	5.1	7.2	ns
t_{ENZL}	Enable-to-Pad, Z to L	1.3	1.5	1.7	2.0	2.8	ns
t_{ENZH}	Enable-to-Pad, Z to H	2.7	3.1	3.5	4.1	5.7	ns
t_{ENLZ}	Enable-to-Pad, L to Z	3.0	3.5	3.9	4.6	6.4	ns
t_{ENHZ}	Enable-to-Pad, H to Z	3.4	3.9	4.4	5.1	7.2	ns
d_{TLH}^3	Delta Low to High	0.016	0.016	0.02	0.022	0.032	ns/pF
d_{THL}^3	Delta High to Low	0.026	0.03	0.032	0.04	0.052	ns/pF
5 V TTL Output Module Timing⁴							
t_{DLH}	Data-to-Pad Low to High	2.4	2.8	3.1	3.7	5.1	ns
t_{DHL}	Data-to-Pad High to Low	3.1	3.5	4.0	4.7	6.6	ns
t_{DHLS}	Data-to-Pad High to Low—low slew	7.4	8.5	9.7	11.4	15.9	ns
t_{ENZL}	Enable-to-Pad, Z to L	2.1	2.4	2.7	3.2	4.5	ns
t_{ENZLS}	Enable-to-Pad, Z to L—low slew	7.4	8.4	9.5	11.0	15.4	ns
t_{ENZH}	Enable-to-Pad, Z to H	2.4	2.8	3.1	3.7	5.1	ns
t_{ENLZ}	Enable-to-Pad, L to Z	3.6	4.2	4.7	5.6	7.8	ns
t_{ENHZ}	Enable-to-Pad, H to Z	3.1	3.5	4.0	4.7	6.6	ns
d_{TLH}^3	Delta Low to High	0.014	0.017	0.017	0.023	0.031	ns/pF
d_{THL}^3	Delta High to Low	0.023	0.029	0.031	0.037	0.051	ns/pF
d_{THLS}^3	Delta High to Low—low slew	0.043	0.046	0.057	0.066	0.089	ns/pF

Notes:

1. All -3 speed grades have been discontinued.
2. Delays based on 50 pF loading.
3. To obtain the slew rate, substitute the appropriate Delta value, load capacitance, and the V_{CCI} value into the following equation:

$$\text{Slew Rate [V/ns]} = (0.1 * V_{CCI} - 0.9 * V_{CCI}) / (C_{load} * d_{T[LH|HL|HLS]})$$

where C_{load} is the load capacitance driven by the I/O in pF
 $d_{T[LH|HL|HLS]}$ is the worst case delta value from the datasheet in ns/pF.
4. Delays based on 35 pF loading.

208-Pin PQFP				
Pin Number	A54SX08A Function	A54SX16A Function	A54SX32A Function	A54SX72A Function
1	GND	GND	GND	GND
2	TDI, I/O	TDI, I/O	TDI, I/O	TDI, I/O
3	I/O	I/O	I/O	I/O
4	NC	I/O	I/O	I/O
5	I/O	I/O	I/O	I/O
6	NC	I/O	I/O	I/O
7	I/O	I/O	I/O	I/O
8	I/O	I/O	I/O	I/O
9	I/O	I/O	I/O	I/O
10	I/O	I/O	I/O	I/O
11	TMS	TMS	TMS	TMS
12	V _{CCI}	V _{CCI}	V _{CCI}	V _{CCI}
13	I/O	I/O	I/O	I/O
14	NC	I/O	I/O	I/O
15	I/O	I/O	I/O	I/O
16	I/O	I/O	I/O	I/O
17	NC	I/O	I/O	I/O
18	I/O	I/O	I/O	GND
19	I/O	I/O	I/O	V _{CCA}
20	NC	I/O	I/O	I/O
21	I/O	I/O	I/O	I/O
22	I/O	I/O	I/O	I/O
23	NC	I/O	I/O	I/O
24	I/O	I/O	I/O	I/O
25	NC	NC	NC	I/O
26	GND	GND	GND	GND
27	V _{CCA}	V _{CCA}	V _{CCA}	V _{CCA}
28	GND	GND	GND	GND
29	I/O	I/O	I/O	I/O
30	TRST, I/O	TRST, I/O	TRST, I/O	TRST, I/O
31	NC	I/O	I/O	I/O
32	I/O	I/O	I/O	I/O
33	I/O	I/O	I/O	I/O
34	I/O	I/O	I/O	I/O
35	NC	I/O	I/O	I/O

208-Pin PQFP				
Pin Number	A54SX08A Function	A54SX16A Function	A54SX32A Function	A54SX72A Function
36	I/O	I/O	I/O	I/O
37	I/O	I/O	I/O	I/O
38	I/O	I/O	I/O	I/O
39	NC	I/O	I/O	I/O
40	V _{CCI}	V _{CCI}	V _{CCI}	V _{CCI}
41	V _{CCA}	V _{CCA}	V _{CCA}	V _{CCA}
42	I/O	I/O	I/O	I/O
43	I/O	I/O	I/O	I/O
44	I/O	I/O	I/O	I/O
45	I/O	I/O	I/O	I/O
46	I/O	I/O	I/O	I/O
47	I/O	I/O	I/O	I/O
48	NC	I/O	I/O	I/O
49	I/O	I/O	I/O	I/O
50	NC	I/O	I/O	I/O
51	I/O	I/O	I/O	I/O
52	GND	GND	GND	GND
53	I/O	I/O	I/O	I/O
54	I/O	I/O	I/O	I/O
55	I/O	I/O	I/O	I/O
56	I/O	I/O	I/O	I/O
57	I/O	I/O	I/O	I/O
58	I/O	I/O	I/O	I/O
59	I/O	I/O	I/O	I/O
60	V _{CCI}	V _{CCI}	V _{CCI}	V _{CCI}
61	NC	I/O	I/O	I/O
62	I/O	I/O	I/O	I/O
63	I/O	I/O	I/O	I/O
64	NC	I/O	I/O	I/O
65	I/O	I/O	NC	I/O
66	I/O	I/O	I/O	I/O
67	NC	I/O	I/O	I/O
68	I/O	I/O	I/O	I/O
69	I/O	I/O	I/O	I/O
70	NC	I/O	I/O	I/O

100-TQFP			
Pin Number	A54SX08A Function	A54SX16A Function	A54SX32A Function
1	GND	GND	GND
2	TDI, I/O	TDI, I/O	TDI, I/O
3	I/O	I/O	I/O
4	I/O	I/O	I/O
5	I/O	I/O	I/O
6	I/O	I/O	I/O
7	TMS	TMS	TMS
8	V _{CCI}	V _{CCI}	V _{CCI}
9	GND	GND	GND
10	I/O	I/O	I/O
11	I/O	I/O	I/O
12	I/O	I/O	I/O
13	I/O	I/O	I/O
14	I/O	I/O	I/O
15	I/O	I/O	I/O
16	TRST, I/O	TRST, I/O	TRST, I/O
17	I/O	I/O	I/O
18	I/O	I/O	I/O
19	I/O	I/O	I/O
20	V _{CCI}	V _{CCI}	V _{CCI}
21	I/O	I/O	I/O
22	I/O	I/O	I/O
23	I/O	I/O	I/O
24	I/O	I/O	I/O
25	I/O	I/O	I/O
26	I/O	I/O	I/O
27	I/O	I/O	I/O
28	I/O	I/O	I/O
29	I/O	I/O	I/O
30	I/O	I/O	I/O
31	I/O	I/O	I/O
32	I/O	I/O	I/O
33	I/O	I/O	I/O
34	PRB, I/O	PRB, I/O	PRB, I/O
35	V _{CCA}	V _{CCA}	V _{CCA}

100-TQFP			
Pin Number	A54SX08A Function	A54SX16A Function	A54SX32A Function
36	GND	GND	GND
37	NC	NC	NC
38	I/O	I/O	I/O
39	HCLK	HCLK	HCLK
40	I/O	I/O	I/O
41	I/O	I/O	I/O
42	I/O	I/O	I/O
43	I/O	I/O	I/O
44	V _{CCI}	V _{CCI}	V _{CCI}
45	I/O	I/O	I/O
46	I/O	I/O	I/O
47	I/O	I/O	I/O
48	I/O	I/O	I/O
49	TDO, I/O	TDO, I/O	TDO, I/O
50	I/O	I/O	I/O
51	GND	GND	GND
52	I/O	I/O	I/O
53	I/O	I/O	I/O
54	I/O	I/O	I/O
55	I/O	I/O	I/O
56	I/O	I/O	I/O
57	V _{CCA}	V _{CCA}	V _{CCA}
58	V _{CCI}	V _{CCI}	V _{CCI}
59	I/O	I/O	I/O
60	I/O	I/O	I/O
61	I/O	I/O	I/O
62	I/O	I/O	I/O
63	I/O	I/O	I/O
64	I/O	I/O	I/O
65	I/O	I/O	I/O
66	I/O	I/O	I/O
67	V _{CCA}	V _{CCA}	V _{CCA}
68	GND	GND	GND
69	GND	GND	GND
70	I/O	I/O	I/O

176-Pin TQFP	
Pin Number	A54SX32A Function
145	I/O
146	I/O
147	I/O
148	I/O
149	I/O
150	I/O
151	I/O
152	CLKA
153	CLKB
154	NC
155	GND
156	V _{CCA}
157	PRA, I/O
158	I/O
159	I/O
160	I/O
161	I/O
162	I/O
163	I/O
164	I/O
165	I/O
166	I/O
167	I/O
168	I/O
169	V _{CCI}
170	I/O
171	I/O
172	I/O
173	I/O
174	I/O
175	I/O
176	TCK, I/O

144-Pin FBGA			
Pin Number	A54SX08A Function	A54SX16A Function	A54SX32A Function
G1	I/O	I/O	I/O
G2	GND	GND	GND
G3	I/O	I/O	I/O
G4	I/O	I/O	I/O
G5	GND	GND	GND
G6	GND	GND	GND
G7	GND	GND	GND
G8	V _{CCI}	V _{CCI}	V _{CCI}
G9	I/O	I/O	I/O
G10	I/O	I/O	I/O
G11	I/O	I/O	I/O
G12	I/O	I/O	I/O
H1	TRST, I/O	TRST, I/O	TRST, I/O
H2	I/O	I/O	I/O
H3	I/O	I/O	I/O
H4	I/O	I/O	I/O
H5	V _{CCA}	V _{CCA}	V _{CCA}
H6	V _{CCA}	V _{CCA}	V _{CCA}
H7	V _{CCI}	V _{CCI}	V _{CCI}
H8	V _{CCI}	V _{CCI}	V _{CCI}
H9	V _{CCA}	V _{CCA}	V _{CCA}
H10	I/O	I/O	I/O
H11	I/O	I/O	I/O
H12	NC	NC	NC
J1	I/O	I/O	I/O
J2	I/O	I/O	I/O
J3	I/O	I/O	I/O
J4	I/O	I/O	I/O
J5	I/O	I/O	I/O
J6	PRB, I/O	PRB, I/O	PRB, I/O
J7	I/O	I/O	I/O
J8	I/O	I/O	I/O
J9	I/O	I/O	I/O
J10	I/O	I/O	I/O
J11	I/O	I/O	I/O
J12	V _{CCA}	V _{CCA}	V _{CCA}

144-Pin FBGA			
Pin Number	A54SX08A Function	A54SX16A Function	A54SX32A Function
K1	I/O	I/O	I/O
K2	I/O	I/O	I/O
K3	I/O	I/O	I/O
K4	I/O	I/O	I/O
K5	I/O	I/O	I/O
K6	I/O	I/O	I/O
K7	GND	GND	GND
K8	I/O	I/O	I/O
K9	I/O	I/O	I/O
K10	GND	GND	GND
K11	I/O	I/O	I/O
K12	I/O	I/O	I/O
L1	GND	GND	GND
L2	I/O	I/O	I/O
L3	I/O	I/O	I/O
L4	I/O	I/O	I/O
L5	I/O	I/O	I/O
L6	I/O	I/O	I/O
L7	HCLK	HCLK	HCLK
L8	I/O	I/O	I/O
L9	I/O	I/O	I/O
L10	I/O	I/O	I/O
L11	I/O	I/O	I/O
L12	I/O	I/O	I/O
M1	I/O	I/O	I/O
M2	I/O	I/O	I/O
M3	I/O	I/O	I/O
M4	I/O	I/O	I/O
M5	I/O	I/O	I/O
M6	I/O	I/O	I/O
M7	V _{CCA}	V _{CCA}	V _{CCA}
M8	I/O	I/O	I/O
M9	I/O	I/O	I/O
M10	I/O	I/O	I/O
M11	TDO, I/O	TDO, I/O	TDO, I/O
M12	I/O	I/O	I/O

484-Pin FBGA		
Pin Number	A54SX32A Function	A54SX72A Function
A1	NC*	NC
A2	NC*	NC
A3	NC*	I/O
A4	NC*	I/O
A5	NC*	I/O
A6	I/O	I/O
A7	I/O	I/O
A8	I/O	I/O
A9	I/O	I/O
A10	I/O	I/O
A11	NC*	I/O
A12	NC*	I/O
A13	I/O	I/O
A14	NC*	NC
A15	NC*	I/O
A16	NC*	I/O
A17	I/O	I/O
A18	I/O	I/O
A19	I/O	I/O
A20	I/O	I/O
A21	NC*	I/O
A22	NC*	I/O
A23	NC*	I/O
A24	NC*	I/O
A25	NC*	NC
A26	NC*	NC
AA1	NC*	I/O
AA2	NC*	I/O
AA3	V _{CCA}	V _{CCA}
AA4	I/O	I/O
AA5	I/O	I/O
AA22	I/O	I/O
AA23	I/O	I/O
AA24	I/O	I/O
AA25	NC*	I/O

484-Pin FBGA		
Pin Number	A54SX32A Function	A54SX72A Function
AA26	NC*	I/O
AB1	NC*	NC
AB2	V _{CCI}	V _{CCI}
AB3	I/O	I/O
AB4	I/O	I/O
AB5	NC*	I/O
AB6	I/O	I/O
AB7	I/O	I/O
AB8	I/O	I/O
AB9	I/O	I/O
AB10	I/O	I/O
AB11	I/O	I/O
AB12	PRB, I/O	PRB, I/O
AB13	V _{CCA}	V _{CCA}
AB14	I/O	I/O
AB15	I/O	I/O
AB16	I/O	I/O
AB17	I/O	I/O
AB18	I/O	I/O
AB19	I/O	I/O
AB20	TDO, I/O	TDO, I/O
AB21	GND	GND
AB22	NC*	I/O
AB23	I/O	I/O
AB24	I/O	I/O
AB25	NC*	I/O
AB26	NC*	I/O
AC1	I/O	I/O
AC2	I/O	I/O
AC3	I/O	I/O
AC4	NC*	I/O
AC5	V _{CCI}	V _{CCI}
AC6	I/O	I/O
AC7	V _{CCI}	V _{CCI}
AC8	I/O	I/O

484-Pin FBGA		
Pin Number	A54SX32A Function	A54SX72A Function
AC9	I/O	I/O
AC10	I/O	I/O
AC11	I/O	I/O
AC12	I/O	QCLKA
AC13	I/O	I/O
AC14	I/O	I/O
AC15	I/O	I/O
AC16	I/O	I/O
AC17	I/O	I/O
AC18	I/O	I/O
AC19	I/O	I/O
AC20	V _{CCI}	V _{CCI}
AC21	I/O	I/O
AC22	I/O	I/O
AC23	NC*	I/O
AC24	I/O	I/O
AC25	NC*	I/O
AC26	NC*	I/O
AD1	I/O	I/O
AD2	I/O	I/O
AD3	GND	GND
AD4	I/O	I/O
AD5	I/O	I/O
AD6	I/O	I/O
AD7	I/O	I/O
AD8	I/O	I/O
AD9	V _{CCI}	V _{CCI}
AD10	I/O	I/O
AD11	I/O	I/O
AD12	I/O	I/O
AD13	V _{CCI}	V _{CCI}
AD14	I/O	I/O
AD15	I/O	I/O
AD16	I/O	I/O
AD17	V _{CCI}	V _{CCI}

Note: *These pins must be left floating on the A54SX32A device.